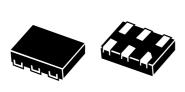


## 4 pin Smart Reset™

Datasheet - production data



UDFN6 (1.00 x 1.45 mm)

#### **Applications**

- Wearable
- Activity tracker
- Smartwatch
- Smartglasses

#### **Features**

- Operating voltage range 2 V to 5.5 V
- Low supply current 1 μA
- Integrated test mode
- Single Smart Reset<sup>™</sup> push-button input with fixed extended reset setup delay (t<sub>SRC</sub>) from 0.5 s to 10 s in 0.5 s steps (typ.), option with internal input pull-up resistor
- Push-button controlled reset pulse duration
  - Option 1: fully push-button controlled, no fixed or minimum pulse width guaranteed
  - Option 2: defined output reset pulse duration (t<sub>REC</sub>), factory-programmed
- Single reset output
  - Active low or active high
  - Push-pull or open drain with optional pullup resistor
- Fixed Smart Reset input logic voltage levels
- Operating temperature: -40 °C to +85 °C
- UDFN6 package 1.00 mm x 1.45 mm
- ECOPACK<sup>®</sup>2 (RoHS compliant, Halogen-Free)

Contents SR1

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SR1 Description

### 1 Description

The Smart Reset<sup>TM</sup> devices provide a useful feature which ensures that inadvertent short reset push-button closures do not cause system resets. This is done by implementing an extended Smart Reset input delay time (t<sub>SRC</sub>), which ensures a safe reset and eliminates the need for a specific dedicated reset button.

This reset configuration provides versatility and allows the application to distinguish between a software generated interrupt and a hard system reset. When the input push-button is connected to the microcontroller interrupt input, and is closed for a short time, the processor can only be interrupted. If the system still does not respond properly, continuing to keep the push-button closed for the extended setup time  $t_{\text{SRC}}$  causes a hard reset of the processor through the reset output.

The SR1 has one Smart Reset input  $(\overline{SR})$  with preset delayed Smart Reset setup time ( $t_{SRC}$ ). The reset output (RST) is asserted after the Smart Reset input is held active for the selected  $t_{SRC}$  delay time. The RST output remains asserted either until the  $\overline{SR}$  input goes to inactive logic level (i.e. neither fixed nor minimum reset pulse width is set) or the output reset pulse duration is fixed for  $t_{REC}$  (i.e. factory-programmed). The device fully operates over a broad  $V_{CC}$  range from 2.0 V to 5.5 V.

#### 1.1 Test mode

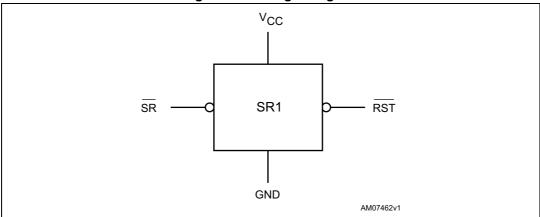
After pulling  $\overline{SR}$  up to  $V_{TEST}$  ( $V_{CC}$  + 1.4 V) or above, the counter starts to count the initial shortened  $t_{SRC-INI}$  (42 ms, typ.). After  $t_{SRC-INI}$  expires, the  $\overline{RST}$  output either goes down for  $t_{REC}$  (if  $t_{REC}$  option is used) or stays low as long as overvoltage on  $\overline{SR}$  is detected (if  $t_{REC}$  option is not used). This is feedback, and the user only knows that the device is locked in test mode. Each time the  $\overline{SR}$  input is connected to ground in test mode, a shortened  $t_{SRC-SHORT}$  ( $t_{SRC}/128$ ) is used instead of regular  $t_{SRC}$  (0.5 s - 10 s). In this way the device can be quickly tested without repeating test mode triggering. Return to normal mode is possible by performing a new startup of the device (i.e.  $V_{CC}$  goes to 0 V and back to its original state).

The advantages of this solution are its high glitch immunity, user feedback regarding entry into test mode, and testability within the full  $V_{CC}$  range.

Description SR1

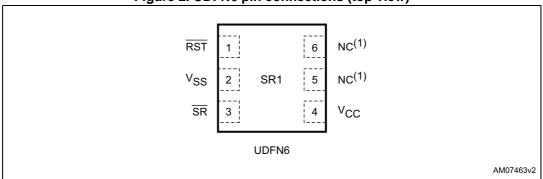
## 1.2 Logic diagram

Figure 1. SR1 logic diagram



#### 1.3 Pin connections

Figure 2. UDFN6 pin connections (top view)



1. Not connected (not bonded); should be connected to  $V_{SS}$ .

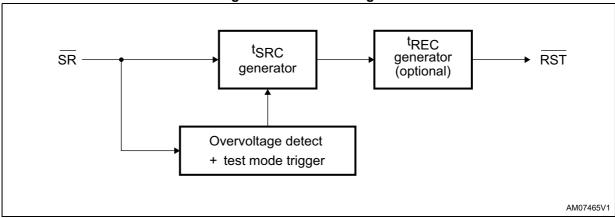
SR1 Device overview

## 2 Device overview

Table 1. Signal names

Pin n°	Name	Туре	Description
1	RST	Output	Reset output, active low, open drain.
2	V <sub>SS</sub>	Supply ground Ground	
3	SR	Input	Smart Reset input, active low.
4	V <sub>CC</sub>	Supply voltage	Positive supply voltage for the device. A 0.1 $\mu F$ decoupling ceramic capacitor is recommended to be connected between $V_{CC}$ and $V_{SS}$ pins.
5	NC	-	Not connected (not bonded); should be connected to V <sub>SS</sub> .
6	NC	-	Not connected (not bonded); should be connected to V <sub>SS</sub> .

Figure 3. SR1 block diagram



Pin descriptions SR1

### 3 Pin descriptions

#### 3.1 Power supply $(V_{CC})$

This pin is used to provide power to the Smart Reset device. A 0.1  $\mu$ F ceramic decoupling capacitor is recommended to be connected between the  $V_{CC}$  and  $V_{SS}$  pins, as close to the SR1 device as possible.

#### 3.2 Power-up sequence

In normal mode, if different input side  $(\overline{SR})$  and  $V_{CC}$  voltage domains are used, power-on sequence must avoid meeting the test mode entry condition to avoid inadvertent test mode entry: there should not be logic high present on the  $\overline{SR}$  input before the  $V_{CC}$  power-up. However  $V_{CC}$  and  $V(\overline{SR})$  rising at the same time is OK (e.g. if both are in the same voltage domain), the device will then safely start into normal operating mode, with  $\overline{RST}$  output inactive (in High-Z mode for open-drain option).

#### 3.3 Ground $(V_{SS})$

This is the ground pin for the device.

### 3.4 Smart Reset input $(\overline{SR})$

Push-button Smart Reset input, active low with optional <u>pull-up</u> resistor.  $\overline{SR}$  input needs to be asserted for at least  $t_{SRC}$  to assert the reset output (RST).

By connecting a voltage higher than  $V_{CC}$  + 1.4 V to the  $\overline{SR}$  input the device enters test mode (see Section 1: Description on page 3 for more information).

### 3.5 Reset output ( $\overline{RST}$ )

RST is active low or active high, open drain or push-pull reset output with optional internal pull-up resistor.

Output reset pulse width is optional as follows:

- Neither fixed nor minimum output reset pulse duration (releasing the push-button while reset output is active, causes the output to de-assert)
- Fixed, factory-programmed output reset pulse duration for t<sub>REC</sub> independent on Smart Reset input state.

### 3.6 RST output undervoltage behavior (for open-drain option)

High-Z on  $\overline{RST}$  output below the specified operating voltage range is guaranteed at  $V_{CC}$  power-on or in case that valid  $V_{CC}$  dropped while the device was idle, i.e. while both output and input were inactive.

5//

## 4 Typical application diagrams

Figure 4. Typical application diagram - input, output and SR1 device in one voltage domain

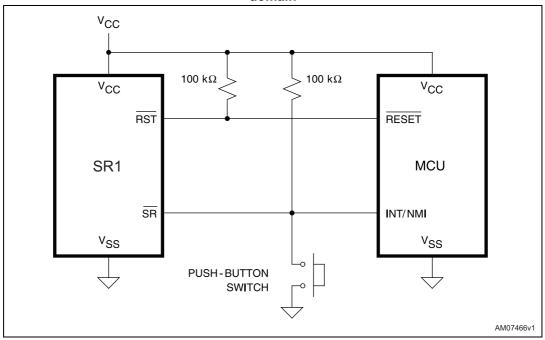
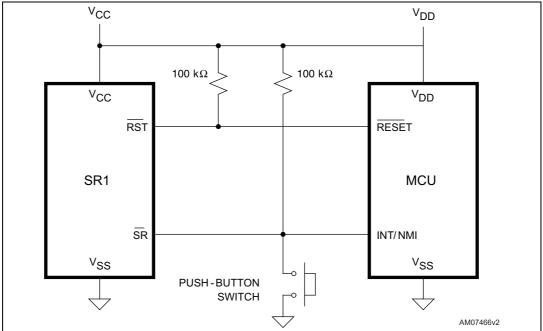


Figure 5. Typical application diagram - SR1 device in a different voltage domain than input and output



Open-drain RST output type and fixed SR input logic threshold allows to use the device in different voltage domains. To prevent entering test mode by creating a condition V(SR) > V<sub>CC</sub> + 1.1 V typ., V<sub>CC</sub> should be powered up before or together with voltage on the SR input.



 $V_{DD}$  $V_{\text{BAT}}$ 100 nF 🖶 100 kΩ · 100 kΩ VCC  $V_{\text{DD}}$ RST RESET SR1 MCU SR INT/NMI  $v_{SS}$  $v_{SS}$ AM07466v3

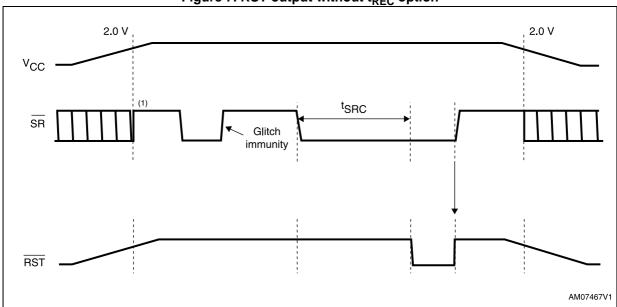
Figure 6. Typical application diagram in different voltage domains - SR input in V<sub>BAT</sub> domain like V<sub>CC</sub> totally disables the test mode



SR1 Timing diagrams

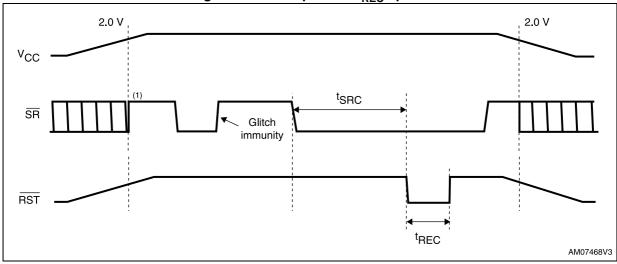
## 5 Timing diagrams

Figure 7.  $\overline{\text{RST}}$  output without  $t_{\text{REC}}$  option



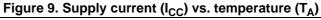
 V<sub>CC</sub> should be powered up before or together with voltage on the SR input to prevent entering test mode by creating a condition V(SR) > V<sub>CC</sub> +1.1 V typ.

Figure 8.  $\overline{\text{RST}}$  output with  $t_{\text{REC}}$  option



 V<sub>CC</sub> should be powered up before or together with voltage on the SR input to prevent entering test mode by creating a condition V(SR) > V<sub>CC</sub> +1.1 V typ.

## 6 Typical operating characteristics



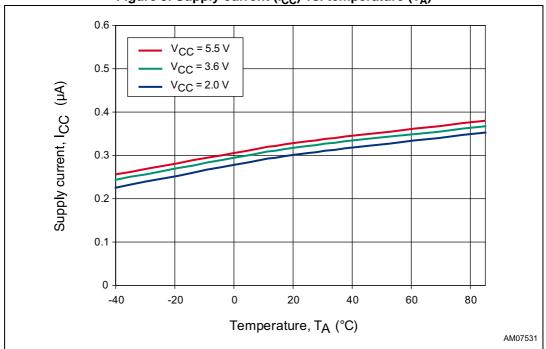
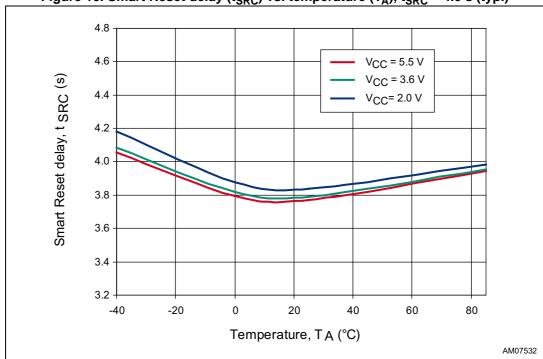


Figure 10. Smart Reset delay ( $t_{SRC}$ ) vs. temperature ( $T_A$ ),  $t_{SRC}$  = 4.0 s (typ.)



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10/21

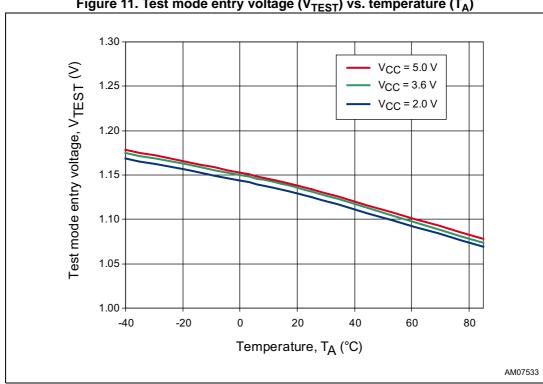
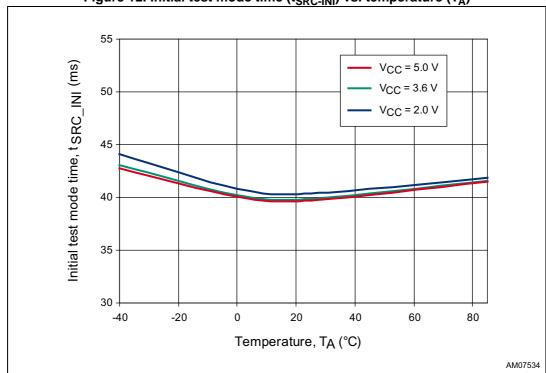


Figure 11. Test mode entry voltage ( $V_{TEST}$ ) vs. temperature ( $T_A$ )





Maximum ratings SR1

### 7 Maximum ratings

Stressing the device above the rating listed in *Table 2: Absolute maximum ratings* may cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions above those indicated in *Table 3: Operating and measurement conditions* of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Refer also to the STMicroelectronics<sup>TM</sup> SURE program and other relevant quality documents.

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
T <sub>STG</sub>	Storage temperature (V <sub>CC</sub> off)	-55 to +150	°C
T <sub>SLD</sub> <sup>(1)</sup>	Lead solder temperature for 10 seconds	260	°C
V <sub>IO</sub>	Input or output voltage	-0.3 to 5.5	V
V <sub>CC</sub>	Supply voltage	-0.3 to 7	V
ESD			
V <sub>HBM</sub>	Electrostatic discharge protection, human body model (JESD22-A114-B level 2)	2	kV
V <sub>RCDM</sub>	Electrostatic discharge protection, charged device model, all pins	1	kV
V <sub>MM</sub>	Electrostatic discharge protection, machine model, all pins (JESD22-A115-A level A)	200	V
	Latch-up (V <sub>CC</sub> pin, SR reset input pin)	EIA/JESD78	

<sup>1.</sup> Reflow at peak temperature of 260 °C. The time above 255 °C must not exceed 30 seconds.



### 8 DC and AC parameters

This section summarizes the operating measurement conditions, and the DC and AC characteristics of the device. The parameters in *Table 4: DC and AC characteristics* are derived from tests performed under the measurement conditions summarized in *Table 3: Operating and measurement conditions*. Designers should check that the operating conditions in their circuit match the operating conditions when relying on the quoted parameters.

Table 3. Operating and measurement conditions

Symbol	Parameter	Value	Unit
V <sub>CC</sub>	Supply voltage	2.0 to 5.5	V
T <sub>A</sub>	Ambient operating temperature	-40 to +85	°C
t <sub>R</sub> , t <sub>F</sub>	Input rise and fall times	≤ 5	ns
	Input pulse voltages	0.2 to 0.8 V <sub>CC</sub>	V
	Input and output timing reference voltages	0.3 to 0.7 V <sub>CC</sub>	V



Table 4. DC and AC characteristics

Symbol	Parameter	Test conditions <sup>(1)</sup>	Min.	Typ. <sup>(2)</sup>	Max.	Unit
V <sub>CC</sub>	Supply voltage		2.0		5.5	V
Icc	Supply current	SR = V <sub>CC</sub> , t <sub>REC</sub> and t <sub>SRC</sub> counter is not running		0.4	1.0	μA
		$V_{CC} \ge 4.5 \text{ V, sinking } 3.2 \text{ mA}$			0.3	V
V <sub>OL</sub>	Reset output voltage low	$V_{CC} \geq 3.3 \text{ V, sinking } 2.5 \text{ mA}$			0.3	V
		$V_{CC} \ge 2.0 \text{ V, sinking 1 mA}$			0.3	V
4	Reset timeout delay,	(daving option)	140	210	280	ms
t <sub>REC</sub>	factory-programmed	(device option)	240	360	480	ms
R <sub>PUO</sub>	Internal out <u>put p</u> ull-up resistor on RST	(device option)		65		kΩ
I <sub>LO</sub>	Output leakage current	V <sub>RST</sub> = 5.5 V, open drain device option without output pull-up resistor	-0.1		0.1	μA
Smart Rese	et					
1	Creart Decet delev	$T_A = -40 \text{ to } +85 ^{\circ}\text{C}$	0.8 x t <sub>SRC</sub>	4 (3)	1.2 x t <sub>SRC</sub>	- s
t <sub>SRC</sub>	Smart Reset delay	T <sub>A</sub> = 25 °C	0.9 x t <sub>SRC</sub>	t <sub>SRC</sub> <sup>(3)</sup>	1.1 x t <sub>SRC</sub>	
V <sub>IL</sub>	SR input voltage low		V <sub>SS</sub> -0.3		0.3	V
V <sub>IH</sub>	SR input voltage high		0.85		5.5	V
R <sub>PUI</sub>	Internal inp <u>ut p</u> ull-up resistor on SR	(device option)		65		kΩ
I <sub>LEAK</sub>	SR input leakage current	device option without input pull-up resistor	-0.1		0.1	μA
	Input glitch immunity			t <sub>SRC</sub>		S
Test mode	•					•
V <sub>TEST</sub>	Test mode entry voltage		V <sub>CC</sub> +0.9	V <sub>CC</sub> +1.1	V <sub>CC</sub> +1.4	V
t <sub>SRC-INI</sub>	Initial test mode time		28	42	56	ms
t <sub>SRC-SHORT</sub>	Shortened Smart Reset delay			t <sub>SRC</sub> / 128		ms

<sup>1.</sup> Valid for ambient operating temperature  $T_A$  = -40 to +85 °C,  $V_{CC}$  = 2.0 to 5.5 V.

<sup>2.</sup> Typical values are at 25 °C and  $V_{CC}$  = 3.3 V unless otherwise noted.

<sup>3.</sup> Factory-programmable in the range of 0.5 s to 10 s typ. in 0.5 s steps.

SR1 Package information

## 9 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: <a href="www.st.com">www.st.com</a>. ECOPACK is an ST trademark.

Figure 13. UDFN6, (1.00 x 1.45 x 0.50 mm), 0.50 mm pitch package outline

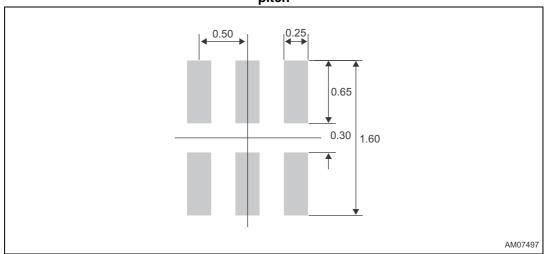
Package information SR1

Table 5. UDFN6, (1.00 x 1.45 x 0.50 mm), 0.50 mm pitch package mechanical data

	Dimensions						
Symbol	(mm)			(inches)			Note <sup>(1)</sup>
	Min.	Тур.	Max.	Min.	Тур.	Max.	
Α	0.50	0.55	0.60	0.0197	0.0217	0.0236	
A1	0.00	0.02	0.05	0.000	0.0008	0.0020	
b	0.18	0.25	0.30	0.0071	0.0098	0.0118	
D	1.40	1.45	1.50	0.0551	0.0571	0.0591	
Е	0.95	1.00	1.05	0.0374	0.0394	0.0413	
е	0.45	0.50	0.55	0.0177	0.0197	0.0217	
k	0.20			0.0079			
L	0.30	0.35	0.40	0.0118	0.0138	0.0157	

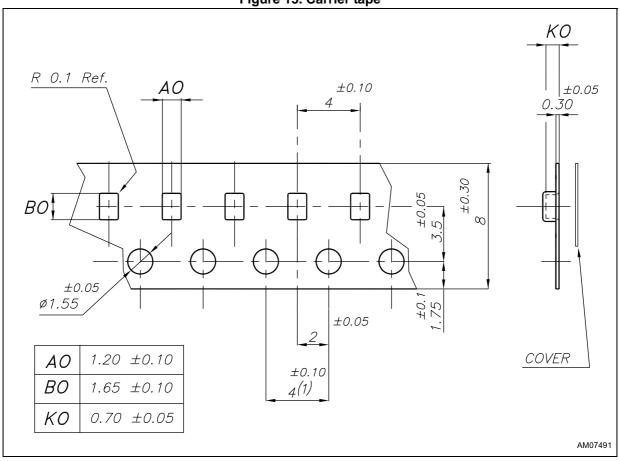
<sup>1.</sup> Package outline exclusive of any mold flashes dimensions and metal burrs.

Figure 14. Footprint recommendation for UDFN6 (1.00 x 1.45 x 0.50 mm), 0.50 mm pitch



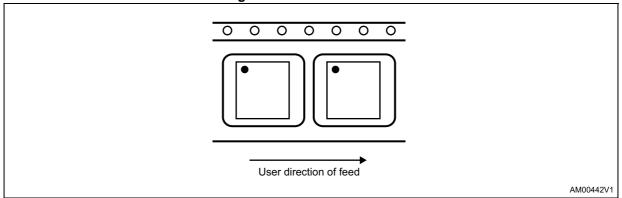
## 10 Tape and reel information

Figure 15. Carrier tape



1. 10-sprocket hole pitch cumulative tolerance ±0.20.

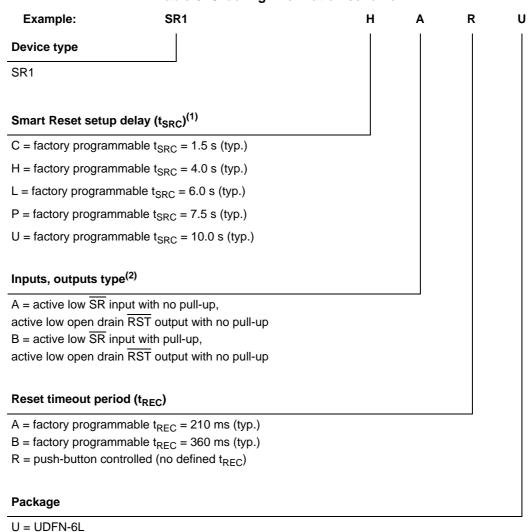
Figure 16. Pin 1 orientation



Part numbering SR1

### 11 Part numbering

Table 6. Ordering information scheme



Smart Reset delay (t<sub>SRC</sub>) is available from 0.5 s to 10 s in 0.5 s steps (typ.). Minimum order quantities may apply. Contact local sales office for availability.

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Push-pull reset output type also available (active low or active high). SR input and open drain reset output
available with optional pull-up resistor. Minimum order quantities may apply. Contact local sales office for
availability.

## 12 Package marking information

Table 7. Package marking

Part number	t <sub>SRC</sub> (s)	Smart Reset inputs <sup>(1)</sup>	Output type <sup>(2)</sup>	t <sub>REC</sub>	Package	Topmark
SR1CARU	1.5	AL	OD, AL	No t <sub>REC</sub>	UDFN6	CA
SR1HARU	4.0	AL	OD, AL	No t <sub>REC</sub>	UDFN6	HA
SR1LARU	6.0	AL	OD, AL	No t <sub>REC</sub>	UDFN6	LA
SR1PAAU	7.5	AL	OD, AL	210 ms	UDFN6	РВ
SR1PARU	7.5	AL	OD, AL	No t <sub>REC</sub>	UDFN6	PA
SR1PBBU	7.5	AL + pull-up	OD, AL	360 ms	UDFN6	PC
SR1UARU	10.0	AL	OD, AL	No t <sub>REC</sub>	UDFN6	UA

- 1. AL = active low.
- 2. OD = open drain, AL = active low.
- 3. No  $t_{REC}$  = push-button controlled reset pulse width, any other value represents typical value of  $t_{REC}$ .

A = dot (pin 1 reference)
B = marking area (topmark)

Revision history SR1

# 13 Revision history

**Table 8. Document revision history** 

Date	Revision	Changes	
10-Mar-2014	1	Initial release	
13-May-2014	2	Modified t <sub>REC</sub> values <i>Table 4 on page 14</i>	

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